## Notice of References Cited Application/Control No. O9/877,820 Applicant(s)/Patent Under Reexamination JAIN ET AL. Examiner Andrew C. Lee Application/Control No. Applicant(s)/Patent Under Reexamination JAIN ET AL. Page 1 of 1

## U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-5,603,096	02-1997	Gilhousen et al.	455/69
	В	US-6,553,235	04-2003	Bark et al.	455/453
	С	US-6,128,506	10-2000	Knutsson et al.	455/522
	D	US-6,775,541	08-2004	Dillon et al.	455/422.1
	Ε	US-6,799,045	09-2004	Brouwer, Frank	455/453
	F	US-5,722,051	02-1998	Agrawal et al.	455/69
	G	US-6,337,973	01-2002	Agin et al.	455/69
	Н	US-6,615,053	09-2003	Lee et al.	455/522
	-	US-6,097,697	08-2000	Yao et al.	370/230
	J	US-6,516,196	02-2003	Chen et al.	455/450
	к	US-5,974,106	10-1999	Dupont et al.	375/377
	L	US-5,603,096	02-1997	Gilhousen et al.	455/69
	М	US-6,477,143	11-2002	Ginossar, Dror	370/230

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	α					
	R					
	S					
	Т					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	w	
	х	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.